





# Are Aged Cells More Dangerous Than Fresh Cells?

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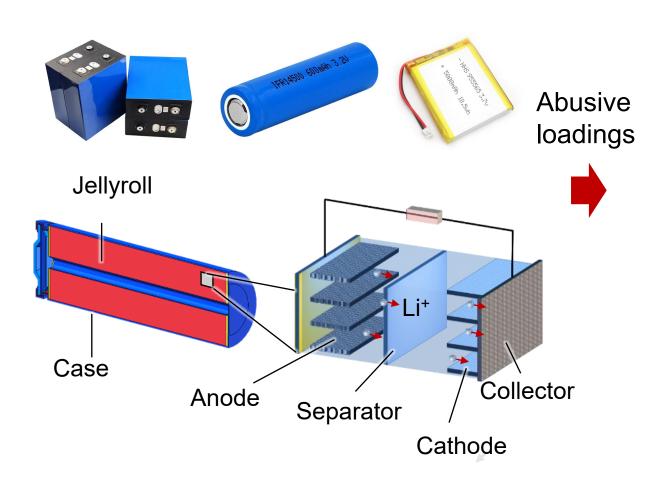
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### Safety issues of LIBs

### Battery cell



### Battery related accident

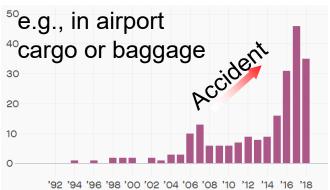
EV Battery energy storage system





Cell phone





https://qz.com/1371531/deep-learning-algorithms-are-being-used-to-detect-lithium-ion-batteries-in-airport-luggage/



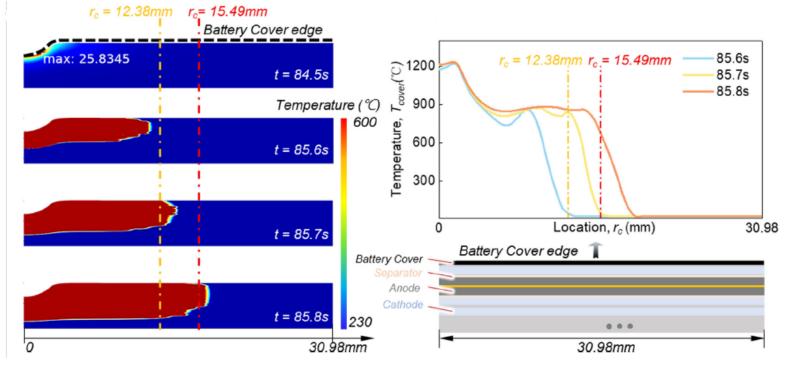
### Evolution processes of safety issues

#### Typical milestone events Thermal runaway Explosion/fire Deformation Internal Short Circuit ISC evolution TR and TR TR propagation ISC triggering propagation processes and Key mechanisms within packs consequences **Problems** TR and TR Possible Safety risk level Criteria to propagation **Solutions** predict ISC risk evaluation modeling

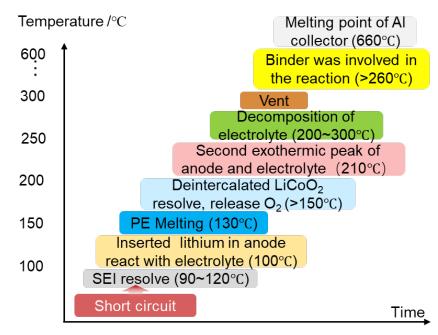


### Evolution processes of safety issues

### ISC evolution processes



### TR evolution processes

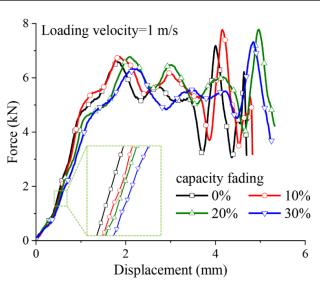


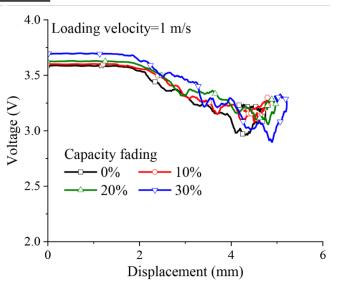
Duan et al., *Energy Storage Materials*, 2022 Feng et al., *J. Power Sources*, 2014

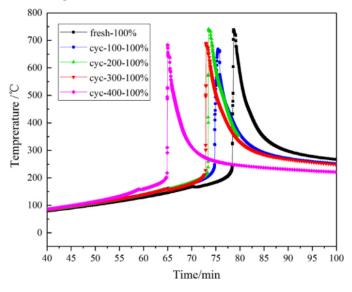


### Cycle-aging effect on safety behaviors

### Aged cell is more dangerous in thermal abuse condition







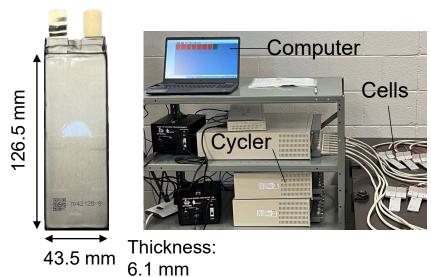
**Aged cells** may have some performance degradation caused by, e.g., loss of lithium inventory (LLI) and loss of active material (LAM)

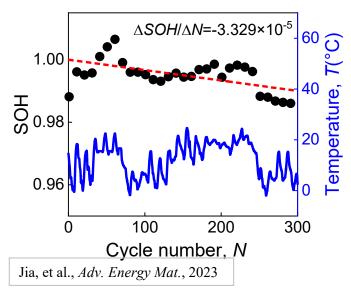
Current research efforts focus on a **single aspect** of the safety risk, which leads to biased conclusions

- Liu et al., *International Journal of Impact Engineering*, 2022 Zhao, et al., *Journal of Energy Storage*, 2020
- Electrochemical integrity
- ISC mode
- TR behavior (triggering and hazards)



### Cycling test

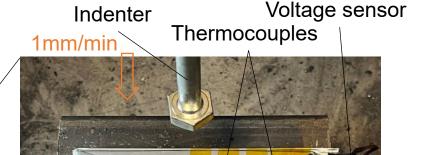




### Short circuit triggering test

Mechanical testing machine





3mm dimeter sphere ball

10 mm

40 mm

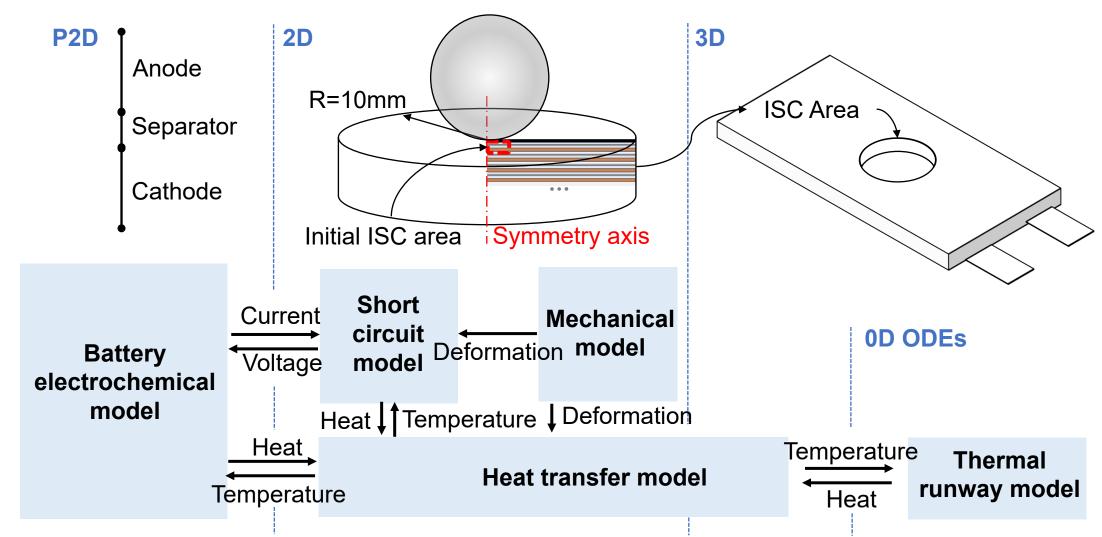


Multimeter

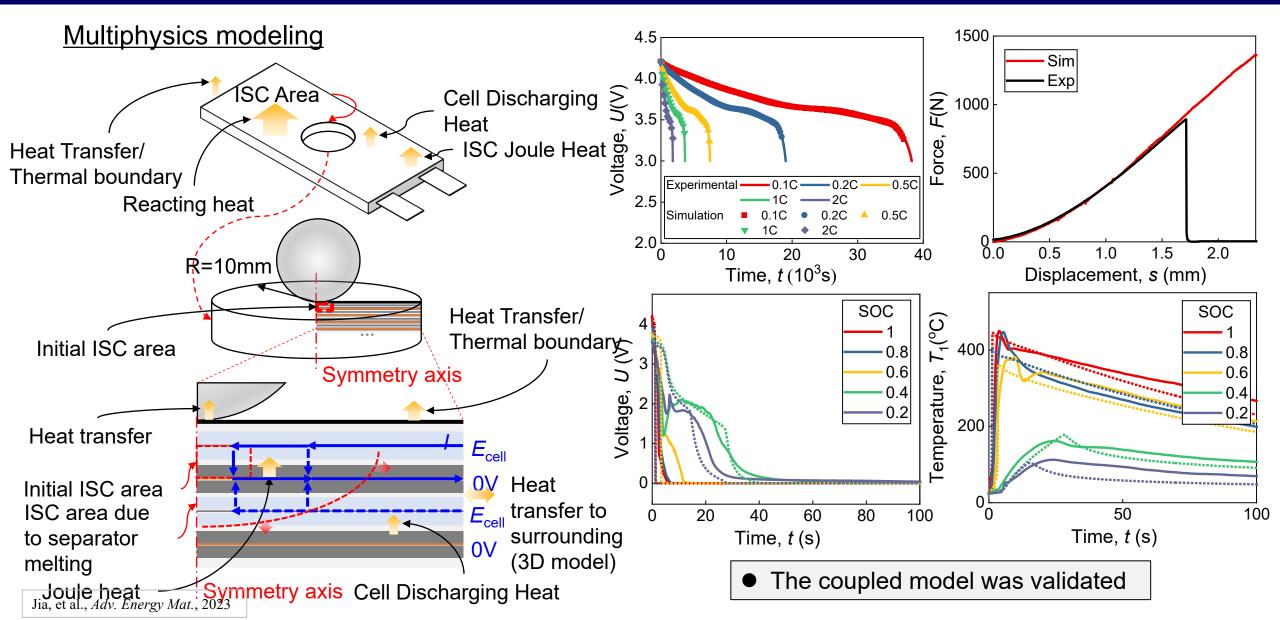
- Pouch cells with NCMA/graphite anode, 3.2 Ah
- Cycle numbers from 1~300 and SoCs from 20% to 100%



### Multiphysics modeling

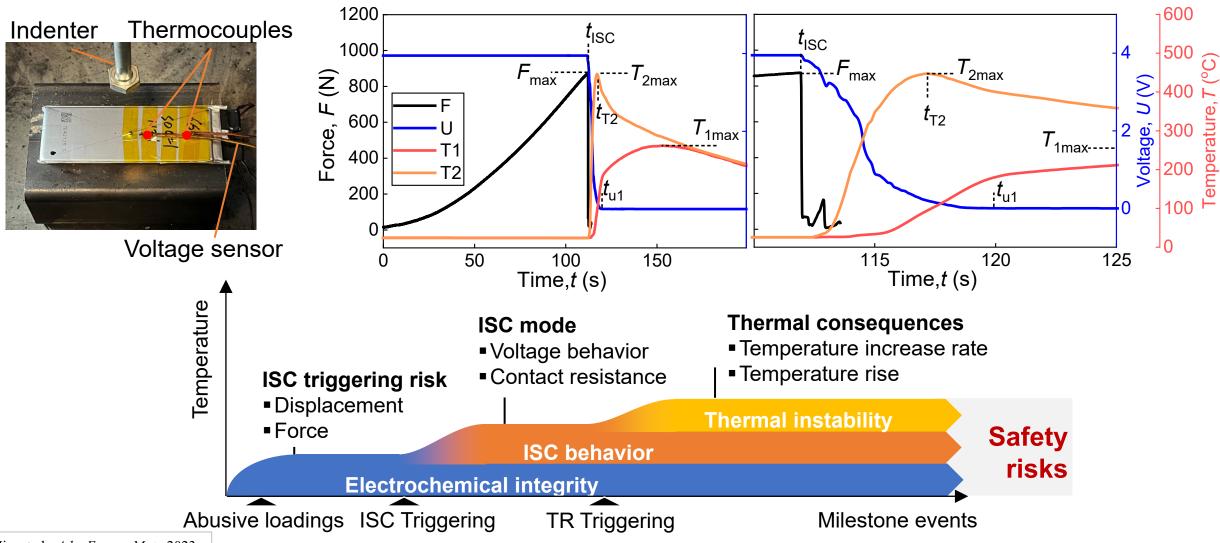








### **Evaluation methods**





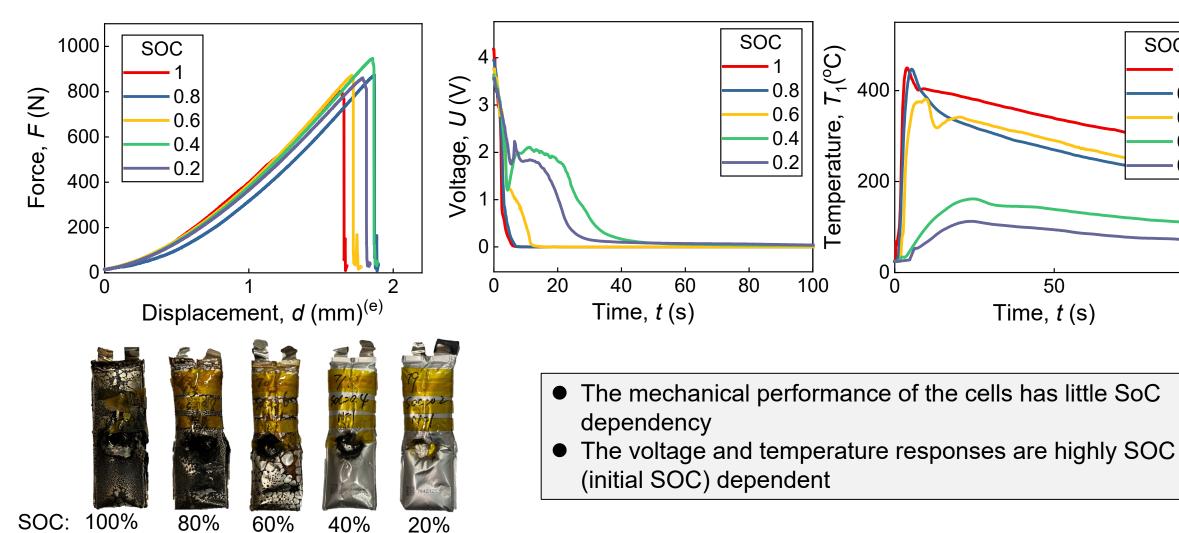
SOC

0.6

0.4

100

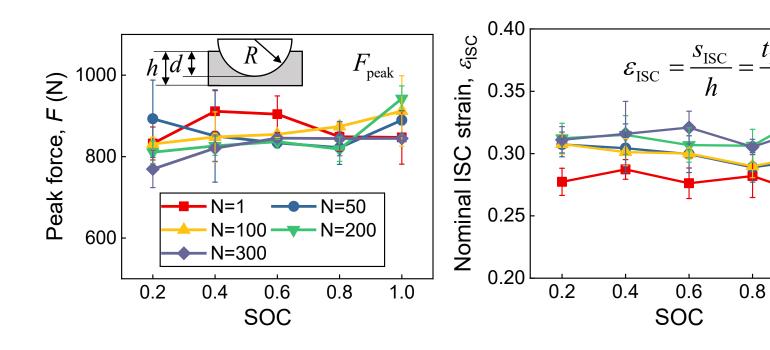
### Typical results for different SOCs

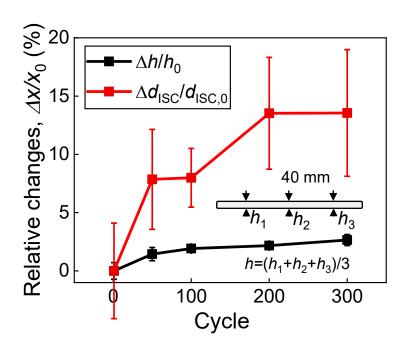


Jia, et al., Adv. Energy Mat., 2023



### Cycle-aging effects on the mechanical behaviors



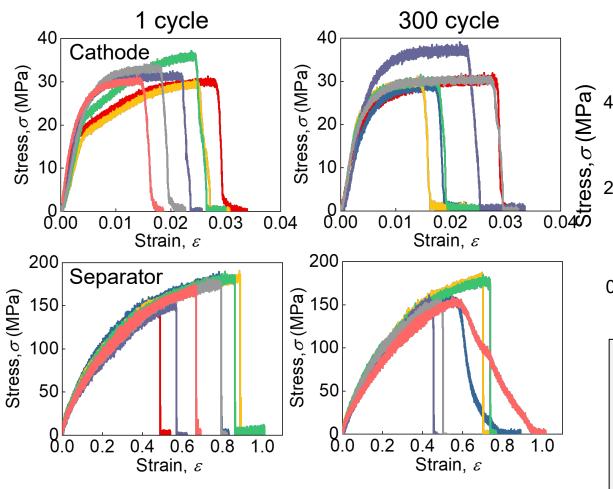


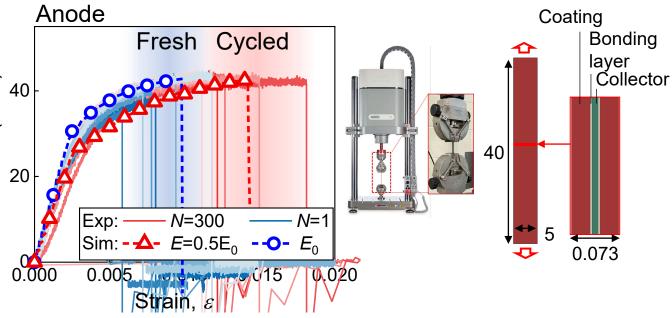
- F<sub>peak</sub> has no obvious relationship to both the cycle number N and SOC
- Nominal ISC strain is not SOC dependent but positively correlated with N
- The thickness cannot be a responsible reason since the thickness increase will actually decrease ISC displacement

1.0



### Cycle-aging effects on the mechanical behaviors

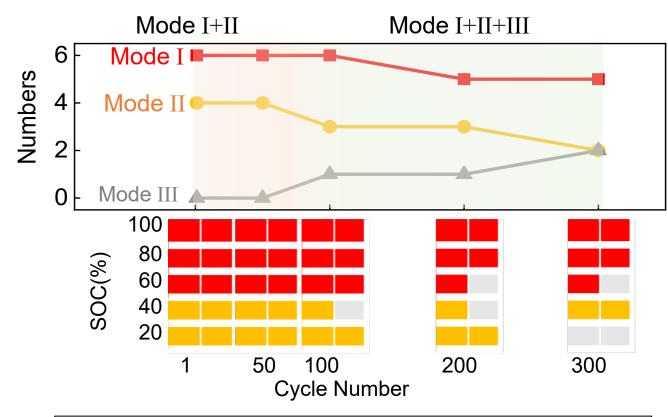




- The mechanical properties of anode and separator change little
- The failure strain of the cathode becomes larger
- Possible reason: Young's modulus of the cathode Al collector decreases due to side reactions [1]



### Cycle-aging effects on the ISC modes



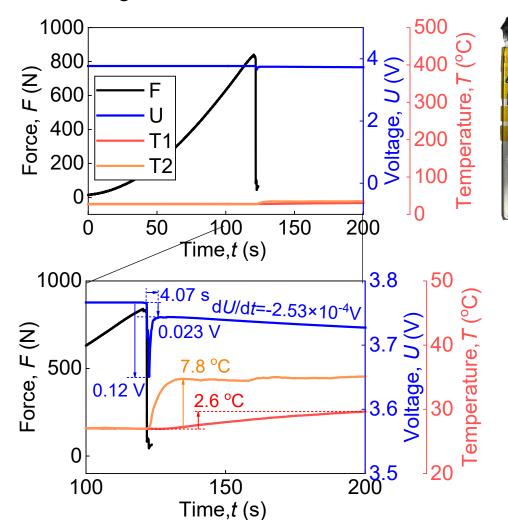
**Mode I**: TR triggered;

Mode II: irrecoverable major ISC and no TR;

**Mode III**: Voltage recovered with minor ISC

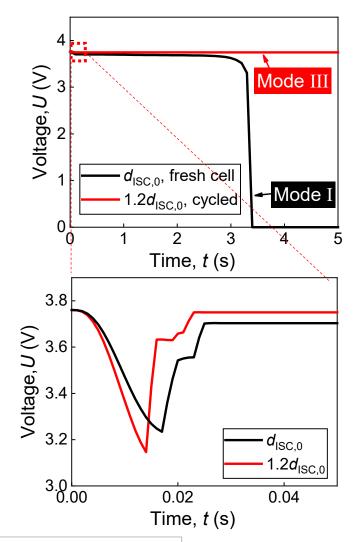
The ISC modes of the aged cells also become milder

### Voltage recovered case, Mode III

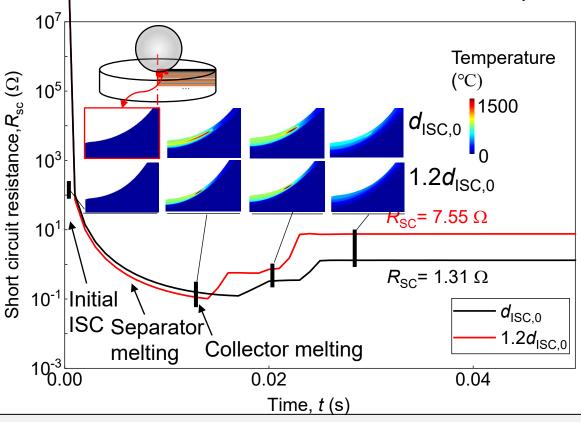




### Cycle-aging effects on the ISC modes



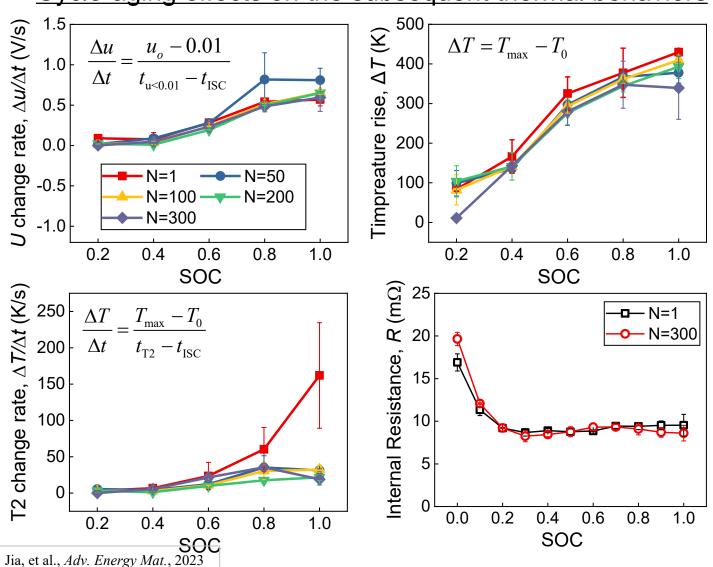
Simulation results of cell with different ISC displacement

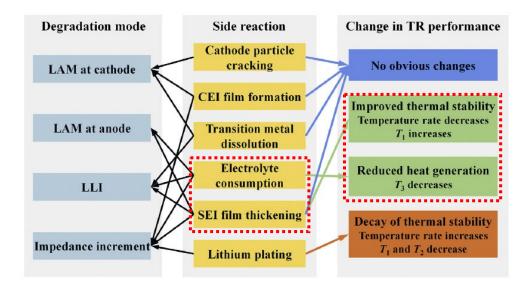


- Due to the large deformation and small deformed thickness of the layers, R<sub>isc</sub> of the aged cell is smaller
- If R<sub>isc</sub> is large enough, the propagation of ISC cannot be maintained



### Cycle-aging effects on the subsequent thermal behaviors





- The temperature rise and temperature increasing rate decrease
- Reasons: electrolyte consumption and solid electrolyte interphase (SEI) film thickening [2, 3]

[2] D. Ren, eTransportation, 2019

[3] X. Feng, *Appl. Energy*, 2019

# **CONCLUDING REMARKS**



The safety risks were quantitively evaluated from three aspects: **ISC triggering risk, ISC modes**, and the **subsequent thermal behaviors**:

 The triggering risks are lower (pouch cells): the increased nominal ISC triggering strain

- The ISC modes
   become milder
   (pouch cells): the
   voltage recovery occurs
   more frequently in
   medium SoC cells.
- Subsequent thermal behaviors are also safer (pouch cells): the decreased temperature change rate and the decreased maximum temperature rise.

Upon mechanical abusive loading, the overall safety for aged cells are slighter better vs. fresh cells



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